

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.:	10/736,386	)	
Filed:	December 15, 2003	)	Conf. No.: 6227
Title:	<b>METHOD FOR CALCULATING HIGH-RESOLUTION WAFER PARAMETER PROFILES</b>	)	
Inventors:	Bruce Whitefield et al.	)	
Art Unit:	2128	)	
Examiner:	Kimberly A. Thornwell	)	
Atty. Ref:	03-1345	)	

**RESPONSE TO THE ADVISORY ACTION MAILED SEPTEMBER 11, 2008**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application and in response to the Office Action mailed July 7, 2008, kindly enter the Office Action response filed on September 4, 2008. Also, please consider the following remarks in response to the Advisory Action mailed September 11, 2008.